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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/730,388	12/07/2003	Paul M. Buxton	TAI.0800	4630

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Please find below and/or attached an Office communication concerning this application or proceeding.

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10/730,388	12/7/03	Buxton	

EXAMINER	
Cindy Khuu	
ART UNIT	**PAPER**
2863	20070123

DATE MAILED:

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Commissioner for Patents

The information disclosure statement filed 12/22/2006 fails to comply with 37 CFR 1.98(a)(2), which requires a legible copy of each cited foreign patent document; each non-patent literature publication or that portion which caused it to be listed; and all other information or that portion which caused it to be listed. It has been placed in the application file, but the information referred to therein has not been considered. The followings are a list of NPLs require a legible copy: Tobin, "Automatic Classification of Spatial Signatures on Semiconductor Wafermaps"; Kameyama, "Semiconductor Defect Classification using Hyperellipsoid Clustering Neural Networks and Model Switching"; and Kamowski, "The Application of Spatial Signature Analysis to Electrical Test Data".

NPL document, "Mining IC test data to optimize VLSI testing" submitted 12/28/06 are now considered.

John Barlow
Supervisory Patent Examiner
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chk 1/23/07